

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application No.	10/576,405
		Filing Date	April 30, 2007
		First Named Inventor	Hada et al.
		Art Unit	1795
<i>(Multiple sheets used when necessary)</i>		Examiner	Anca Eoff
SHEET 1 OF 2		Attorney Docket No.	SHIGA7.048APC

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number <i>Number - Kind Code (if known)</i> Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
/A.E./	1	2004/0186216	09-23-2004	Satoh et al.	
	2	6,887,644	05-03-2005	Nozaki et al.	Corresponds to No. 23
	3	6,596,458	07-22-2003	Sato et al.	Corresponds to No. 17
	4	6,013,416	01-11-2000	Nozaki et al.	Corresponds to Nos. 21 and 22
	5	5,968,713	10-19-1999	Nozaki et al.	Corresponds to No. 26
	6	6,656,659	12-02-2003	Nozaki et al.	Corresponds to No. 27
	7	2002/150834	10-17-2002	Yamamoto et al.	Corresponds to No. 29
	8	5,554,664	09-10-1996	Lamanna et al.	
	9	6,358,665	03-19-2002	Pawlowski et al.	
	10	2003/0049456	03-13-2003	Kawasato et al.	
	11	6,344,304	02-05-2002	Takechi et al.	
	12	2005/0203262 A1	09-15-2005	Feiring et al.	
	13	2005/0014090	01-20-2005	Hirayama et al.	
↓	14	6,958,206	10-25-2005	Tsuchimura et al.	
/A.E./	15	6,423,799	07-23-2002	Berneth et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document <i>Country Code-Number-Kind Code</i> Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	<b>T<sup>1</sup></b>
/A.E./	16	WO 2002/077116	10-03-2002	Daikin Industries, Ltd.		✓ abstract
	17	JP 2000-321771	11-24-2000	Fuji Photo Film Co., Ltd.		✓ abstract
	18	JP 2001-002735	01-09-2001	Mitsubishi Rayon Co Ltd		✓
	19	JP 2004-057449	02-26-2004	Matsushita Electric Ind Co Ltd		✓
	20	JP H07-234511	09-05-1995	Fujitsu Ltd		✓ abstract
	21	JP H09-073173	03-18-1997	Fujitsu Ltd		✓ abstract
	22	JP H09-090637	04-04-1997	Fujitsu Ltd		✓ abstract
↓	23	JP H11-012326	01-19-1999	Fujitsu Ltd		✓ abstract
/A.E./	24	JP H04-039665	02-10-1992	Fujitsu Ltd		✓ abstract

Examiner Signature	/Anca Eoff/	Date Considered	03/17/2009
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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**T<sup>1</sup>** - Place a check mark in this area when an English language Translation is attached.

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/A.E./	25	JP H05-346668	12-27-1993	Fujitsu Ltd		✓ abstract
↓	26	JP H10-161313	06-19-1998	Fujitsu Ltd		✓ abstract
↓	27	JP H10-319595	12-04-1998	Fujitsu Ltd		✓ abstract
↓	28	EP 0663616	10-30-2002	Fujitsu Ltd	Corresponds to No. 20	
/A.E./	29	JP 2002-311587	10-23-2002	Fujitsu Ltd		✓ abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
/A.E./	30	PRZYBILLA K.J. et al., "Hexafluoroacetone in Resist Chemistry: A Versatile New Concept for Materials for Deep UV Lithography", SPIE Vol. 1672 <i>Advances in Resist Technology and Processing IX</i> (1992), pages 500-512.	

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